



11-18-.04

2133

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By: *[Handwritten signature]*  
LINDA E. HASTINGS

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No. 50-1290.

Attorney Docket No.: NEKO 19.481 (100806-00091)

IN THE UNITED STATES PATENT AND TRADEMARK  
OFFICE

Inventor: Kazunori KISHIMOTO  
Serial No.: 10/083,447  
Filed: February 26, 2002  
Title: **METHOD OF TESTING A SEMICONDUCTOR  
INTEGRATED CIRCUIT AND METHOD AND  
APPARATUS FOR GENERATING TEST PATTERNS**  
Examiner: John P. Trimmings  
Group Art Unit: 2133

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

AMENDMENT

S I R :

In response to the Office Action mailed on August 17,  
2004, the period for responding thereto having been set to  
expire after November 17, 2004, please amend the subject  
application as follows: